DOCUMENT CHANGE REQUEST

DCR number 1375	Changes required for: General	Originator: Steve Thacker
Date: 2021/02/18	Date sent: 2020/09/16	Organisation: ESCC Executive Secretariat
Status: IMPLEMENTED		

Title:	Generic Specification for Discrete Semiconductor Components		
Number:	5000	Issue:	9

Other documents affected:

Page:

29, 41, 42

Paragraph:

new 8.25, Chart F4A

Original wording:

See ESCC 5000 issue 9

Proposed wording:

Test requirements for Internal Gas Analysis is added for SPQ as follows; see attached mark-up specification ESCC5000 Draft 10 for details:

1) Add new Para. 8.25 as follows:
"8.25 INTERNAL GAS ANALYSIS
MIL-STD-883, Test Method 1018."

2) In Chart F4A, add Internal Gas Analysis as the first test in the Assembly Capability Subgroup with applicable new note 6 as follows. The original note 6 is deleted.
"6. Only applicable to the qualification testing phase for single phase qualification (SPQ)."

Justification:

As required by PSWG & ESA review of IGA within ESCC 5000 (based around the same test already included in ESCC9000)

Attachments:
escc5000_draft10a_in_review.docx
Modifications:
N/A
Approval signature:
Date signed:
2021-02-18